

To Advance Wafer Test Technology

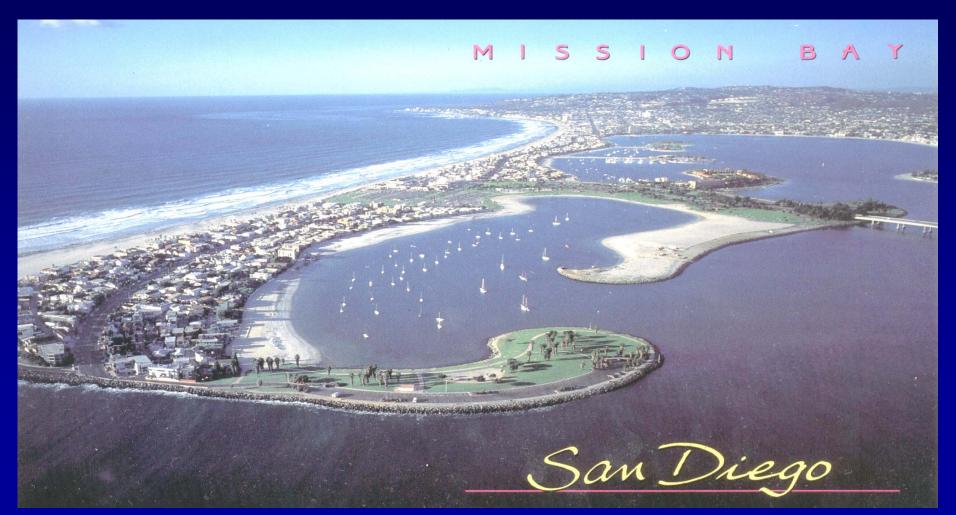
To Serve and Inform the Wafer Test Professional

o To Boldly Go Where No Workshop Has Gone Before

San Diego, CA, June 11 to 14, 2006



16th Annual SWTW



IEEE SWTW - 2006 June 11 to 14



- "THE" Conference for Wafer Test Professionals
- Sponsored by the IEEE Computer Society and the Test Technology Technical Council
- A balance mixture of semiconductor manufacturer and supplier presentations
- It's a **Probe Technology Forum**
- Provides practical solutions to real problems
- Great social activities & informal discussions
- Meet new people & <u>have a little fun!</u>



"Who's Fault Is It?"

Organization and Technical Program

- William Mann, SWTW General Chair
- Jerry Broz, Ph.D., International Test Solutions, Program Chair
- Maddie Harwood, CEM Inc, Registration and Finance Chair

Steering Committee

- Nadine Aldahhan, Freescale
- Jack Courtney, IBM
- Bret Crump, Micron Technologies
- Michael Egloff, AMD
- Michael Harris, Texas Instruments
- Ken Karklin, Agilent Technologies

- Ger Koch, Philips Semiconductor
- Rey Rincon, SV Probe
- Roger Sinsheimer, Xandex
- Tim Swettlen, Intel
- Fred Taber, BiTS Workshop
- Bill Williams, At Large



Silence your cell phone !!!



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Technical Program

Sunday, June 11, 2006

- Registration & Exhibits
- Dinner
- Probe Year In Review
- Keynote Speaker:

Mike Campbell VP Engineering Qualcomm



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Technical Program

Monday, June 12

- Continental Breakfast
- High Volume Manufacturing
- Multi DUT & High Pin Methodology
- Lunch
- Pad Damage Control
- Exhibits Open From 3:00 t0 5:00 PM
- Busses to Aerospace Museum at 5:30
- Tour and Buffer Dinner



Technical Program

Tuesday, June 13

- Continental Breakfast
- Contact Resistance Studies
- Large Area Probing
- Lunch
- SEMATECH Presentation
- Probe Metrology Panel
- Free Time for Networking
- Exhibits Open From 5:00 7:00
- "Team Techno Trivia" after dinner

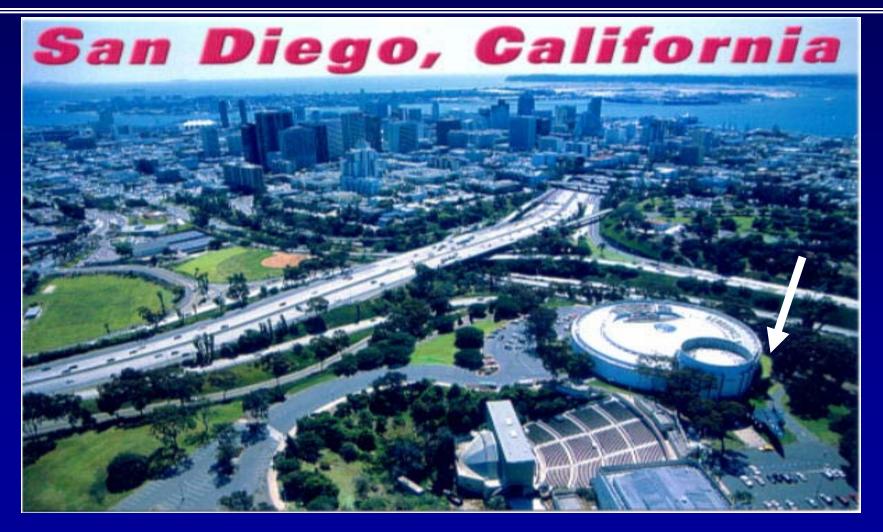


Wednesday, June 14

- Continental Breakfast
- Probe Potpourri
- Probe Test Data Management
- Best Presentation Awards
- Adjournment and Lunch



Aerospace Museum



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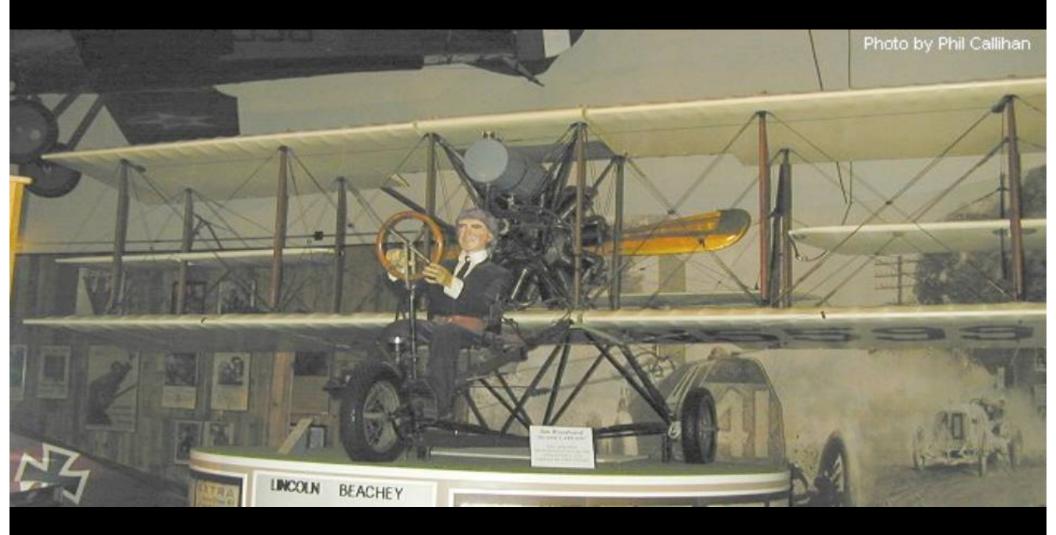
















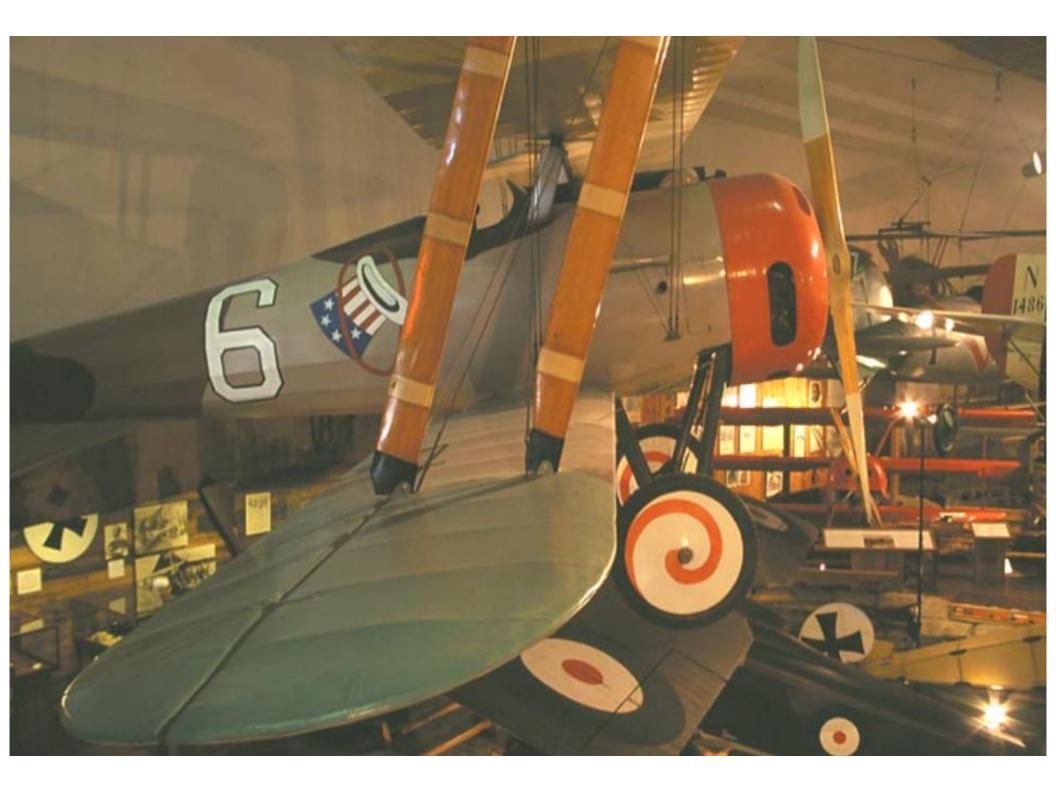




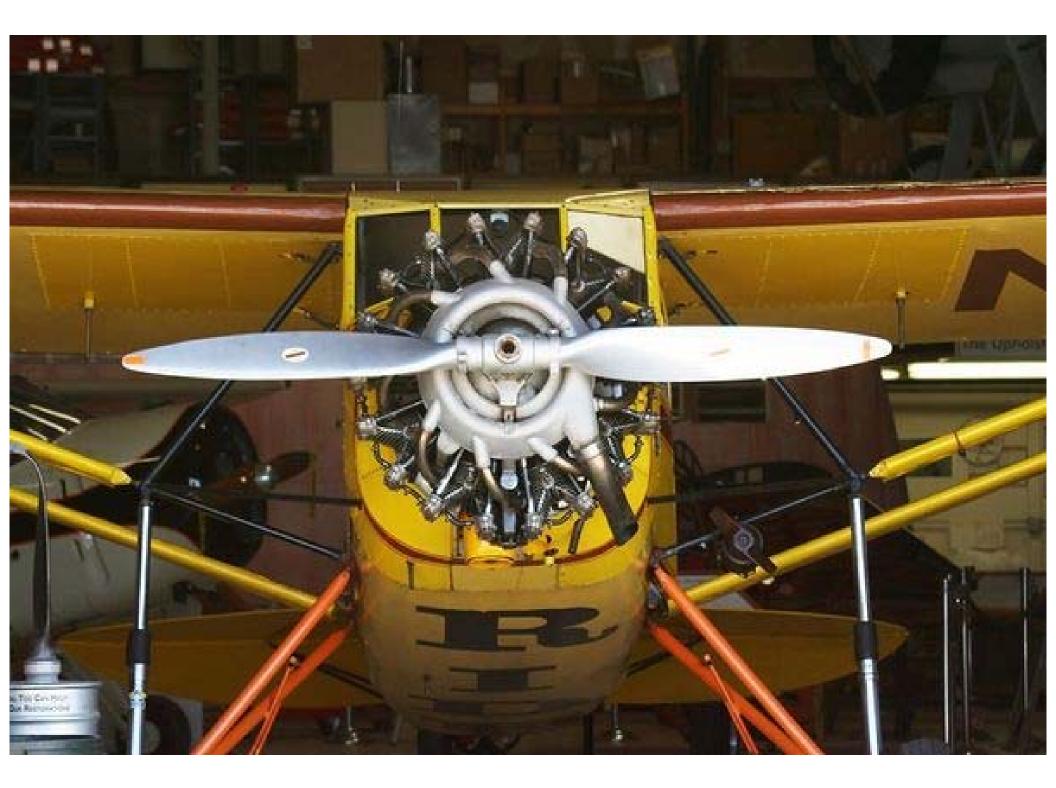


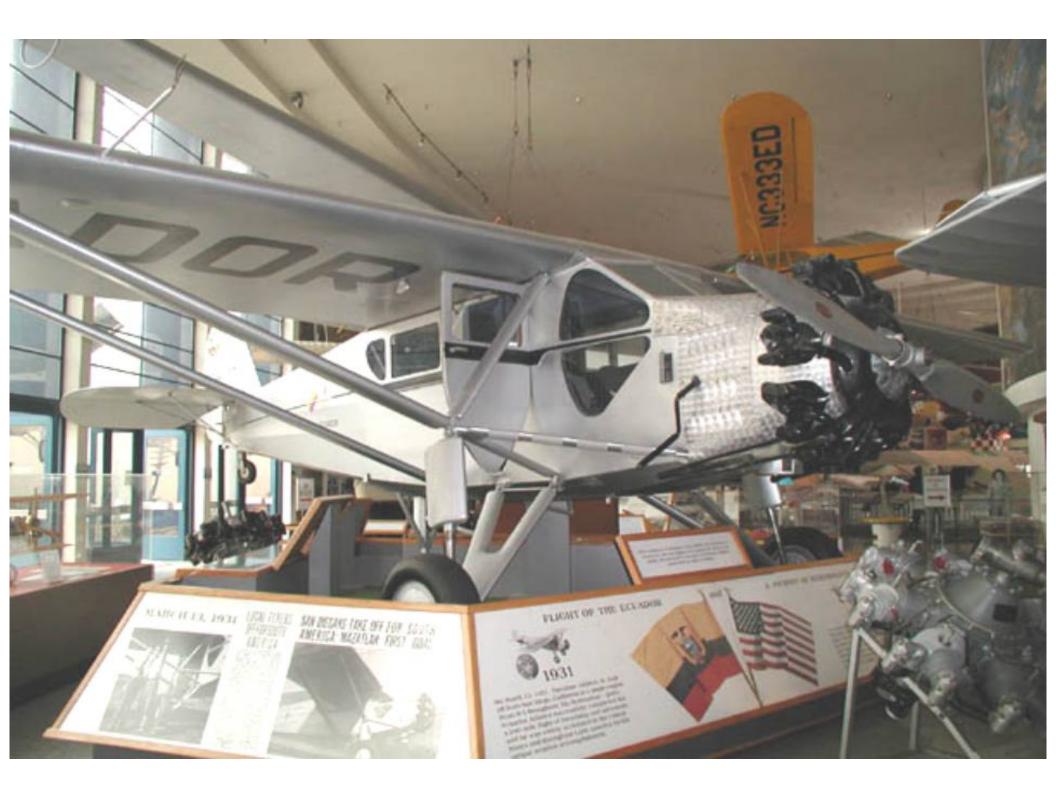












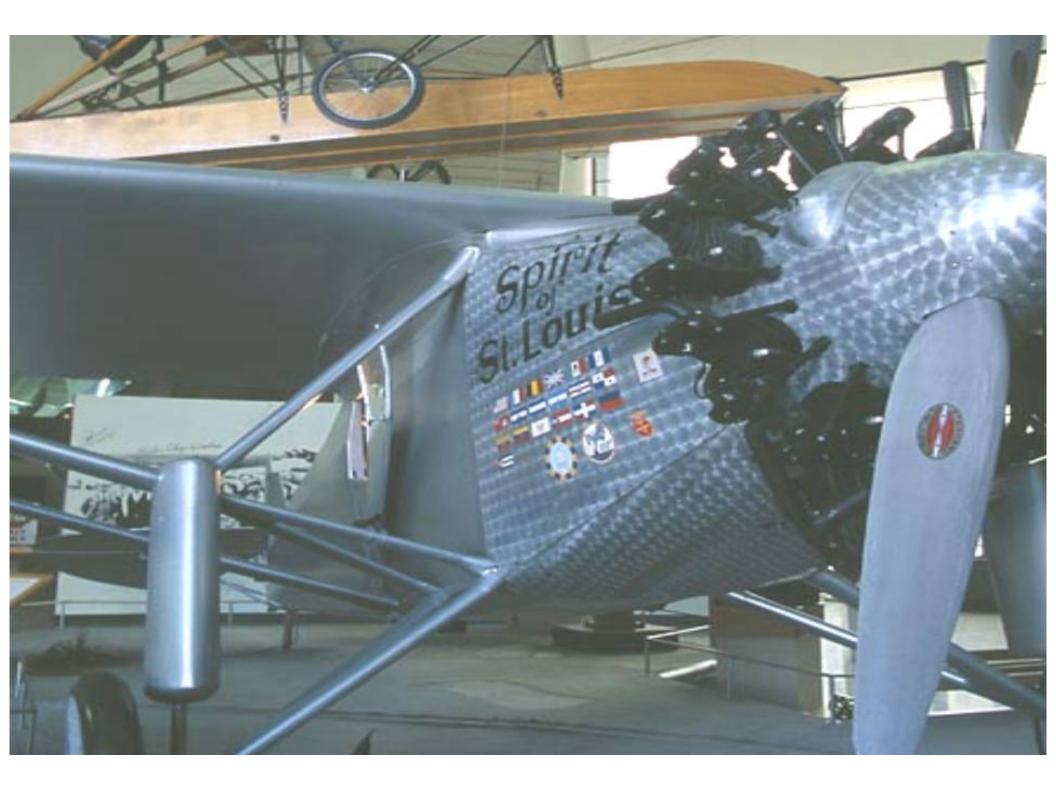


Photo by Phil Callihan/AIRPOWER.CALLIHAN.CC





Inflexe









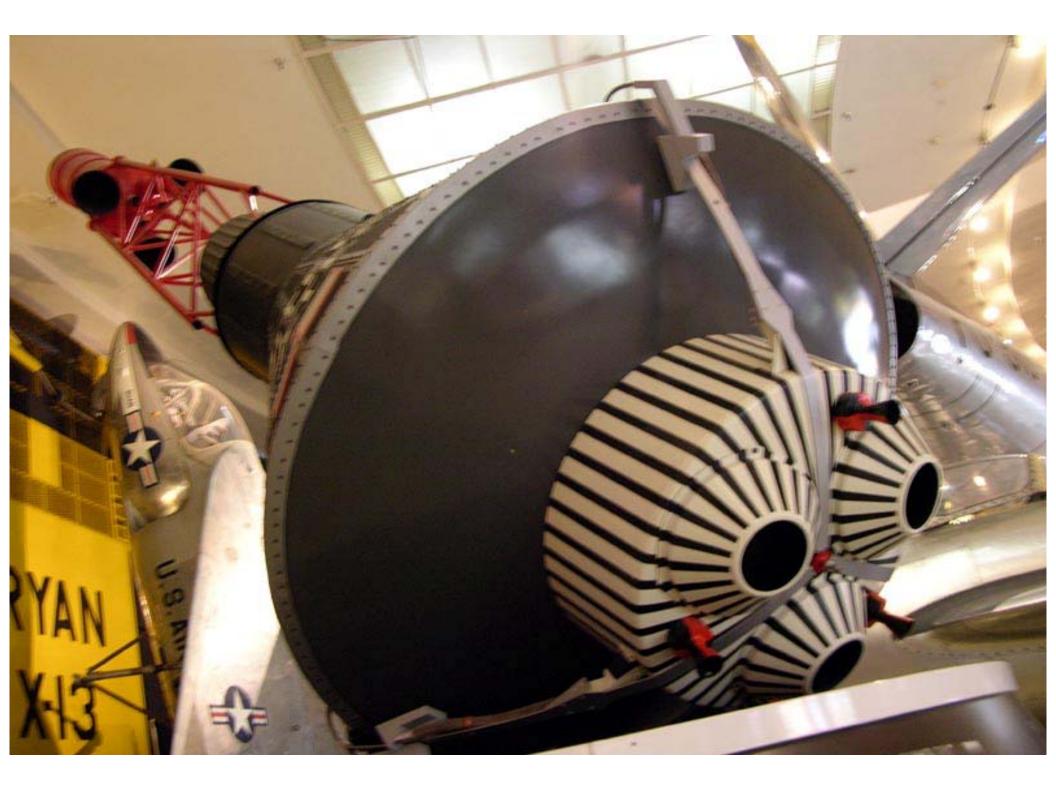


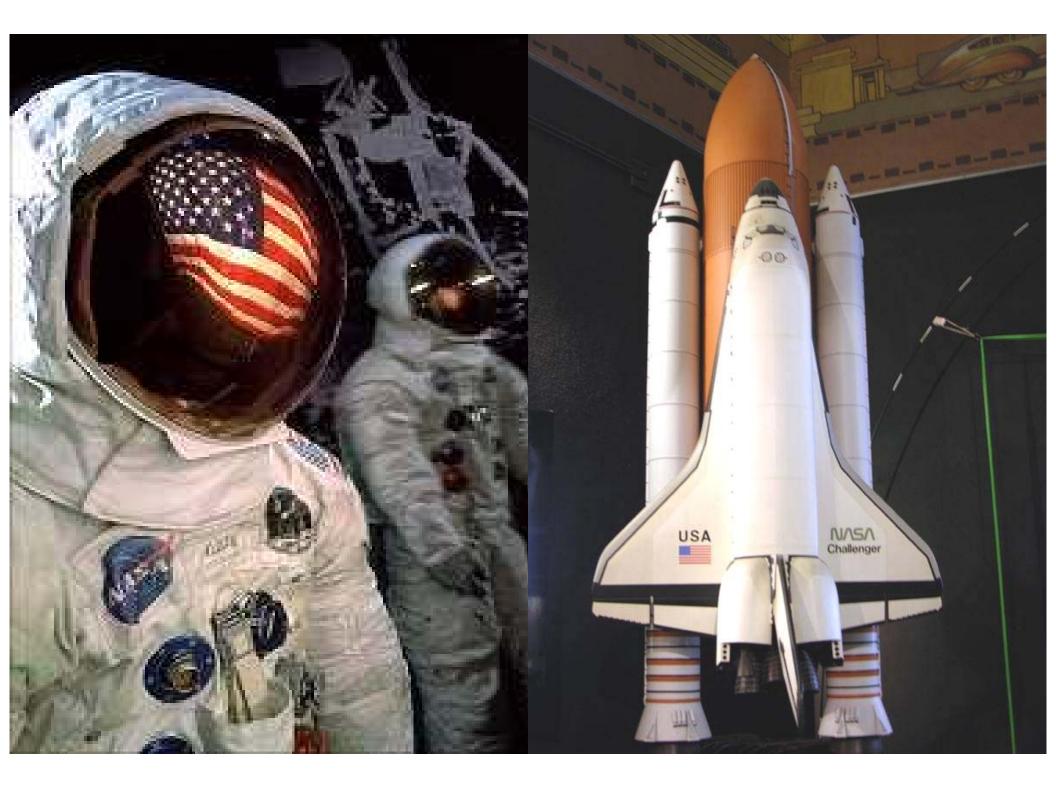










































http://www.swtest.org

Central Online Repository

- Past presentations
- Online registration
- Sign up for our mailing list

• Tremendous continued success!!

- Over seventy-six thousand visits
- Thanks to "web-efforts" of Jerry Broz



- IEEE Recognition
 First SWTW Life Achievement
 Best Overall Presentation
 Best Data Presented
 Best Presentation, Tutorial in Nature
- Most "Inspirational" Presentation
- Other "Special Awards"



Last Year's Winners

Best Overall Presentation

"Comprehensive Approach to Contact Resistance Instability"

Joe Foerstel, Sean Chen (Altera Corporation) Atsushi Mine, Phill Mai (JEM – America) Jerry Broz, Ph.D. (International Test Solutions)

Best Data Presented

"Impact of Vibration on Contact Resistance"

Al Wegleitner (Texas Instruments – Dallas)





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Last Year's Winners

Best Presentation, Tutorial in Nature

"The Probe Card Signature Syndrome"

Frank Pietzschmann (Infineon Technologies) Jim Andersen (Applied Precision, LLC)

Most "Inspirational" Presentation "Cobra FP Probe Card for Logic and Memory Applications"

Lucie Mialhe, Isabelle Garidi, Ph.D., (KNS - France) Bahadir Tunaboylu, Ph.D. (KNS - US)



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The "Special" Award



"What A Load **Of Crap!**" For the Poorest **Disguised Sales** Pitch

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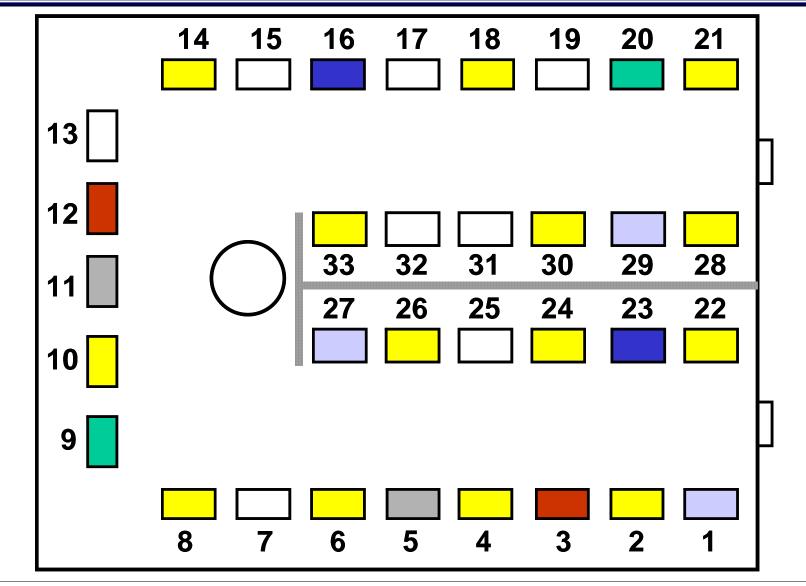
Tabletop Exhibits

- 1. ACCRETECH USA, INC.
- 2. FEINMETALL GMBH
- 3. ADVANCED PROBING SYSTEMS
- 4. SV PROBE
- 5. **TEMPTRONIC CORPORATION**
- 6. APEX AMERICA, INC.
- 7. TEST ADVANTAGE, INC.
- 8. MICRONICS JAPAN CO., LTD
- 9. INTEGRATED TECHNOLOGY CORP.
- **10. CASCADE MICROTECH**
- 11. MACCS/ERS
- 12. POINT TECHNOLOGIES, INC.
- 13. INT'L TEST SOLUTIONS, INC.
- 14. WENTWORTH LABORATORIES, INC.
- 15. OXFORD LASERS, INC.
- **16. REID-ASHMAN MANUFACTURING**

- **17. DYNAMIC TEST SOLUTIONS**
- **18. RD CHEMICAL COMPANY**
- 19. DSL LABS, INC.
- 20. APPLIED PRECISION, LLC
- 21. MICRO PROBE, INC.
- 22. CAMTEK USA
- 23. INTEST SILICON VALLEY CORP
- 24. JEM AMERICA CORP.
- 25. QUALITAU, INC.
- 26. AMST CO., LTD
- 27. ELECTROGLAS, INC.
- 28. FORMFACTOR, INC.
- **29. TOKYO ELECTRON**
- **30. SIGMA PROBE**
- **31. MICRO SUBSTRATES CORPORATION**
- **32. INTEGRATED TEST CORPORATION**
- **33. INT'L CONTACT TECHNOLOGIES**

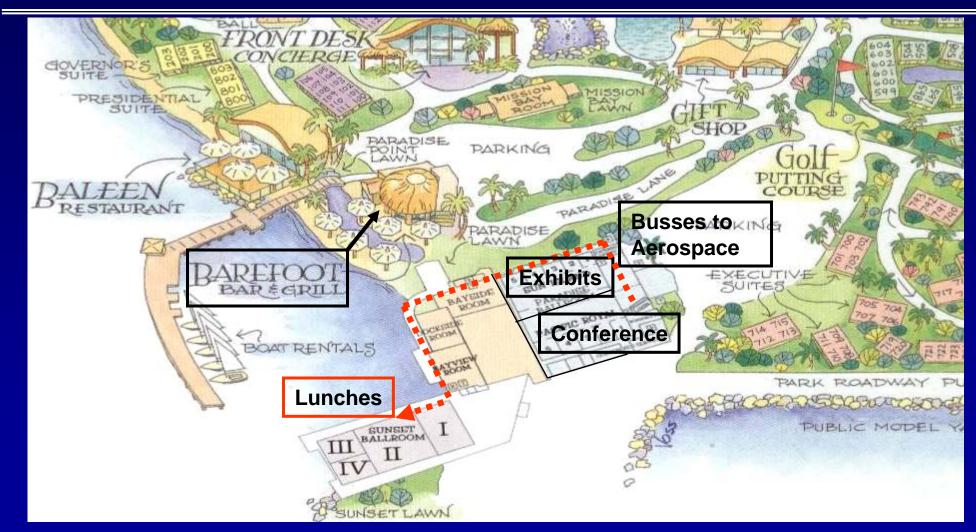


Products and Services Exhibition





Don't Get Lost!

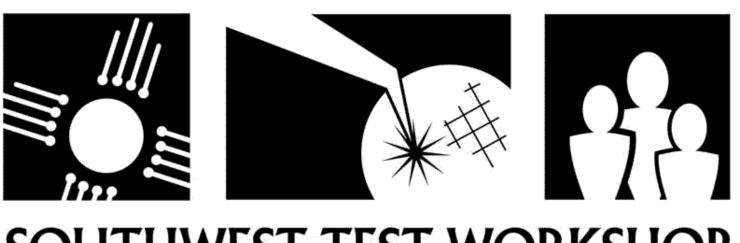


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SOUTHWEST TEST WORKSHOP

To Advance Wafer Test Technology

• To Serve and Inform the Wafer Test Professional

• To Boldly Go Where No Workshop Has Gone Before

San Diego, CA, June 5 to 8, 2005